



Make: Hitachi, Japan  
Model: S-3000H  
Magnification: x 30 – x 3, 00,000  
Specimen size: Max. 150 mm diameter  
Accelerating voltage: 0.3 – 30 kV  
Resolution: 3.5 nm @ 25kV high vacuum mode  
Attachments:

Energy-dispersive X-ray. Spectroscopy (EDS) & Backscattered Electron Detector (BSED)  
Energy dispersive analysis.  
True Windows NT environment  
Image management system for image processing, searching and archiving  
Network capability to transfer SEM images and data to external PCs and servers

Applications:  
To study surface morphology of samples  
Evaluation of crystallographic orientation